# The chemistry of La on the Si(001) surface from rst principles

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This paper reports state-of-the-art electronic structure calculations of La adsorption on the Si(001) surface. We predict La chains in the low coverage limit, which condense in a stable phase at a coverage of  $\frac{1}{5}$  m onolayer. At  $\frac{1}{3}$  m onolayer we predict a chem ically rather inert, stable phase. La changes its oxidation state from La<sup>3+</sup> at lower coverages to La<sup>2+</sup> at coverages beyond  $\frac{1}{3}$  m onolayer. In the latter oxidation state, one electron resides in a state with a considerable contribution from La-d and f states.

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#### I. IN TRODUCTION

D evice scaling has been the engine driving the microelectronics revolution as predicted by M oore's law <sup>1</sup> By reducing the size of transistors, processors become faster and more power e cient at an exponential rate. Currently the main challenge in device scaling is the integration of high-k oxides as gate oxides into silicon technology.

The gate oxide is an integral part of a metal-oxidesem iconductor eld-e ect transistor (M O SFET). It is the dielectric of a capacitor, which is used to attract charge carriers into the channel between source and drain, and thus switches the transistor between its conducting and its non-conducting state. W ith a thickness of approxim ately 1-2 nm,<sup>2</sup> the gate oxide is the smallest structure of a transistor. Further scaling would result in an unacceptably high quantum mechanical leakage current and thus a large power consumption.

In current transistors, the gate oxide ism ade from SiD<sub>2</sub> and SiD<sub>x</sub>N<sub>y</sub>. Future transistor generations will have to employ oxides with a higher dielectric constant (high-k). This allows greater physical thicknesses and thus reduces the quantum mechanical leakage currents. The main contenders for the replacement of SiD<sub>2</sub> in future transistors are, from today's point of view, oxides containing alkaline earth metals like Sr or Ba, third-row elements like Y or La, forth-row elements like Ti, Zr and H f, or mixtures thereof. P rominent examples are per-ovskite structures around SrT iD<sub>3</sub><sup>3</sup> and LaA iD<sub>3</sub><sup>4,5,6</sup>, u-orite structures like ZrO<sub>2</sub> and H fD<sub>2</sub><sup>7</sup> and also Y<sub>2</sub>O<sub>3</sub> and La<sub>2</sub>O<sub>3</sub><sup>8,9</sup> or pyrochlore structures like La<sub>2</sub>H f<sub>2</sub>O<sub>7</sub><sup>10</sup> and La<sub>2</sub>Zr<sub>2</sub>O<sub>7</sub>.<sup>11,12</sup> R ecently, also promising results on P r<sub>2</sub>O<sub>3</sub> have been published.<sup>13</sup>

W hile the rst high-k-oxides will be grown with an interfacial SiO<sub>2</sub> layer, a further reduction in scale requires high-k-oxides with a direct interface to silicon. The requirement to limit interface states, and the offen crystalline nature of the oxides dem and an epitaxial growth of the oxides on silicon. Considering layer-by-layer growth by molecular beam epitaxy (MBE), the rst growth step for high-k oxides is the deposition of the m etal on silicon. Therefore we have investigated deposition of m etals out of the three m ost relevant classes for high-k oxides on Si(001). These are the divalent alkaline-earth m etals and the three- and the four-valent transition m etals. The results on adsorption of Zr and Sr have been published previously.<sup>14,15</sup> The present paper completes the study with a description of La-adsorption on Si(001) as example of a trivalent m etal.

Our previous work has shown that Zr tends to form silicides readily.<sup>14</sup> Silicide grains have been observed after Zr sputtering on  $Si(001)_{r}^{16}$  unless silicide form ation is suppressed by early oxidation which, how ever, leads to interfacial SiO<sub>2</sub>. The Sr silicides are less stable in contact with silicon and due to their sizable mism atch in lattice constant, nucleation does not proceed easily. The alkaline-earth metals Sr and Ba have been used in the rst dem onstration of an atom ically de ned interface between a high-k oxide, namely SrT iO<sub>3</sub> and silicon.<sup>3</sup> By following through the detailed steps of the form ation of this interface, starting at the low -coverage structures of metal adsorption, we were able to provide a new picture for the phase diagram of Sron Si(001).<sup>15</sup> The phase diagram has been in portant to link the theoretical interface structure of SrT iO  $_3$  on Si(001) to the experimental grow th process.<sup>15,17,18</sup> From the interface structure and its chem istry we could show in turn that the band-o set, a critical param eter for a transistor, can be engineered to m atch technological requirem ents by carefully controlling the oxidation of the interface.<sup>17</sup>

Since m any of the characteristics of Sr adsorption carry over to La-adsorption let us brie y sum m arize the m ain results.<sup>15</sup> Sr donates its electrons to the empty dangling bonds of the Si-surface. The Si-dim ers receive electron pairs one-by-one, and unbuckle as they become e charged. W hen all Si dangling bonds are lled, i.e. beyond  $\frac{1}{2}$  m onolayer (M L), additional electrons enter the anti-bonding states of the Si-dim ers at the surface, and thus break up the Si-dim er-row reconstruction.

At low coverage, Sr form s chains running at an angle of 63 to the Sidim er rows. As the coverage increases, the chains condense rst into structures at  $\frac{1}{6}$  M L and at  $\frac{1}{4}$  M L, which are determined by the buckling of the Sidim ers and their electrostatic interaction with the positive Sr ions. At  $\frac{1}{2}$  M L a chemically fairly inert layer form s, where all dangling bonds are led and all ideal adsorption sites in the valley between the Si-dim er row s are occupied.

The paper is organized similar to our previous work on Sr adsorption. In Sec. II we describe the computational details of the calculation. In Sec. III and IV we review brie y the reconstruction of the Si(001) surface and we discuss the known bulk La silicides. Sec. V, V I and V II deal with the low coverage limit, where La adatoms form dimers and chain structures. Beyond the canonical coverage of 1/3 M L (Sec. V III) we observe a change in the oxidation state of the La ad-atoms from 3+ to 2+ (Sec. IX). The results are placed into context in Sec. X where we propose a phase diagram for La on the surface. The computational supercells used for the simulation of the low-coverage structures are shown in the appendix.

### II. COMPUTATIONALDETAILS

The calculations are based on density functional theory<sup>19,20</sup> using a gradient corrected functional.<sup>21</sup> The electronic structure problem was solved with the projector augmented wave (PAW) method, 22,23 an all-electron electronic structure method using a basis set of plane waves augmented with partial waves that incorporate the correct nodal structure. The frozen core states were im ported from the isolated atom . For the silicon atom swe used a set with two projector functions per angular momentum for s and p-character and one projector per angular m om entum with d-character. The hydrogen atom s saturating the back surface had only one s-type projector function. For lanthanum we treated the 5s and 5p core shells as valence electrons. W e used two projector functions permagnetic quantum number for the s, p, and f angularm om entum channels and one for the d channel. The augmentation charge density has been expanded in spherical harm onics up to '= 2. The kinetic energy cuto for the plane wave part of the wave functions was set to 30 Ry and that for the electron density to 60 Ry.

A slab of ve silicon layers was used as silicon substrate. This thickness was found to be su cient in previous studies on Sr adsorption.<sup>15</sup> The dangling bonds of the unreconstructed back surface of the slab have been saturated by hydrogen atom s. The lateral lattice constant was chosen as the experimental lattice constant a = 5:4307 A of silicon,<sup>24</sup> which is 1 % sm aller than the theoretical lattice constant. Since we always report energies of adsorbate structures relative to the energy of a slab of the clean silicon surface, the lateral strain due to the use of the experimental lattice constant cancels out. The slabs repeat every 16 A perpendicular to the surface, which results in a vacuum region of 9.5 A for the The CarParrinello ab-initio molecular dynamics<sup>25</sup> scheme with damped motion was used to optimize the electronic and atomic structures. All structures were fully relaxed without symmetry constraints. The atomic positions of the backplane of the slab and the term inating hydrogen atoms were frozen.

M any of the adsorption structures are m etallic, which requires a su ciently ne grid in k-space. We used an equivalent to twelve by twelve points per  $(1 \ 1)$  surface unit cell. P revious studies have shown that a mesh of eight by eight k-points is su cient.<sup>15</sup> W e have chosen a higher density here as this allow sus to use com m ensurate k-m eshes for 3 and 2 surface reconstructions.

For m etallic system s, the orbital occupations were determ ined using the M erm in functional,<sup>26</sup> which produces a Ferm i-distribution for the electrons in its ground state. The electron tem perature was set to 1000 K. In our case this tem perature should not be considered as a physical tem perature but rather as a broadening scheme for the states obtained with a discrete set of k-points. The M erm in functional adds an entropic term to the total energy, which is approximately canceled by taking the m ean of the total energy U (T) and the M erm in-free energy F (T) = U (T) TS (T) as proposed by G illan;<sup>27</sup>

$$U(T = 0) = \frac{1}{2}(F(T) + U(T)):$$
 (1)

The forces are, however, derived from the freeenergy F (T). The resulting error has been discussed previously.<sup>15</sup>

In order to express our energies in a comprehensible manner, we report all energies relative to a set of reference energies. This set is de ned by bulk silicon and the lowest energy silicide LaSi<sub>2</sub>. The reference energies are listed in Tab. I. The reference energy  $E_0$  [La] for a La atom, corresponding to the coexistence of bulk silicon and bulk La, is extracted from the energy E [LaSi<sub>2</sub>] of the disilicide calculated with a 9 9 3 k-m esh for the tetragonal unitcell with a = 4:326 and c = 13:840 and the reference energy of bulk silicon  $E_0$  [Si] as

$$E_0[La] = E[LaS_{12}] 2E_0[S_{11}]$$
: (2)

The bulk calculation for silicon was performed in the two atom unit cell with a (10 10 10) k-m esh and at the experimental lattice constant of  $5.4307 \text{ A} \cdot \frac{24}{2}$ 

For the surface calculations, we always subtracted the energy of a slab of the clean  $(4 \ 2)$  silicon surface of the same layer thickness and backplane.

#### III. THE SILICON SURFACE

Before discussing the adsorption of La, let us brie y summarize the chemistry of the clean (001) surface

TABLE I: Reference energies used in this paper without frozen core energy. See text for details of the calculation.

	Energy [H]
E o [Si]	-4.0036
E <sub>0</sub> [La]	-32.1395
E <sub>0</sub> <sup>(1 1)</sup> [5 layer-Si-slab]	-21.1139

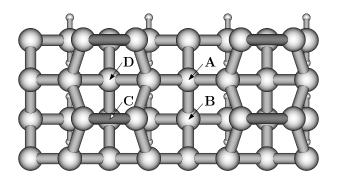


FIG. 1: Top view of the Si(001) surface and the four high symmetry positions spanning the surface irreducible  $(2 \quad 1)$  unit cell. The dimer buckling is not show n.

of silicon. A more detailed account has been given previously.<sup>15</sup>

On the unreconstructed silicon surface, the atom s form a square array. Due to a lack of upper bonding partners, each atom has two singly occupied dangling bonds pointing out of the surface. In order to avoid half-occupied bands, pairs of silicon atom s dim erize, using up one dangling bond per atom to form the dim er bond. This is called the dim er row reconstruction. Still, one dangling bond per silicon atom is half occupied, which drives the so-called buckled-dim er reconstruction: O ne atom of each dim er lifts up and the other shifts down, resulting in a \buckled" dim er. This buckling causes both electrons to localize in the upper, sp<sup>3</sup>-like silicon atom of a dim er, whereas the other, sp<sup>2</sup>-like silicon atom with the empty p-like dangling bond prefers a m ore planar arrangem ent.

Fig. 1 shows a ball stick model of the silicon surface and introduces the high-symmetry adsorption sites A to D, which we will refer to in the following discussion.

Filling the empty dangling bond with two electrons results in a rem oval of the buckling as observed in our studies on Sr adsorption.<sup>15</sup> A s La has an odd number of valence electrons, we also examined the changes of the buckling upon lling the initially empty dangling bond with a single electron. W hile the di erence in z coordinate of the two silicon atom s of a buckled dimer is 0.76A and the one of an unbuckled dimer 0.00A, it is 0.35A after donation of a single electron to a dimer. Thus the am plitude of the dimer buckling may be used as a measure for the electron count.

TABLE II: Energies per La atom of bulk silicides relative to our reference energies (Tab. I).

	E [La] [eV ]	
LaSi <sub>2</sub> (I41=am dS)	0.00	
LaSi (Pnma)	0.42	
LaSi(Cm cm)	0.62	
La3Si2 (P4=mbm)	0.80	

#### IV. BULK LA SILICIDES

In the case of Sr, the chem ical interaction with silicon could be understood by investigating the bulk Sr silicides.<sup>15</sup> All these structures could be explained by the Zintl-K lemm concept.<sup>28</sup> The electropositive Sratom s donate their two valence electrons to the silicon atom s. Each accepted electron saturates one of silicon's four valences. A Si can thus form three covalent bonds, a Si<sup>2</sup> only two, a Si<sup>3</sup> only one and a Si<sup>4</sup> has a closed shell and does not form covalent bonds. This principle was found to also be valid for the surface reconstructions of Sr on Si(001).<sup>15</sup>

The Zr silicides on the other hand cannot be explained by the simple Zintl-K lemm concept.<sup>14</sup> The Zrd states also contribute to the bonding and thus retain a variable num ber of electrons.

Similarly, the La silicides cannot be simply explained by a quasi-ionic interaction with silicon. We nd La in form all charge states between two and three (i.e. charge according to the Zintl-K lemm concept). Also the atom and angularm om entum resolved density of states reveals, that La d states are partly occupied in these structures.

Fig.2 shows the La silicides. LaSi<sub>2</sub> is the lowest energy silicide. The energies per La atom are listed in Table II.

#### V. AD-ATOM SAND LA DIMERS

Our search for the adsorption structures of La have been guided by the electron count rules that emerged from our investigation of  $\mathrm{Sr}^{15}$  adsorption on the same surface. The studies of Sr provided a consistent picture: The electrons from Sr are fully transferred into the Sidim er dangling bonds of the Si substrate. The ordering of Sr atom s on the surface is determ ined by the electrostatic attraction between the Sr-cations and negatively charged Si-ions at the surface. The negative Si-ions are the raised atom s of buckled Si dim ers and the atom s of

lled, and thus unbuckled, dim ers. This picture holds up to coverages where all Sidim ers are lled at 1/2 M L. D ue to the di erent electron count of La as compared to Sr, we expect that the silicon dim ers are lled already at a coverage of 1/3 M L and secondly we anticipate deviations from the above schem e.

E ven though we predict La-chains to be them ost stable structures in the low coverage lim it, we rst investigate

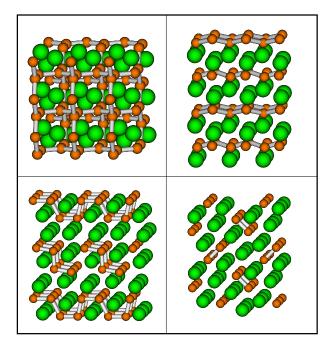


FIG.2: (Color online) The bulk silicide structures. top left: LaSi I41=am dS<sup>29</sup> (lowest energy structure); top right: LaSi Pnm  $a_i^{30}$  bottom left: LaSiCm cm  $i^{31}$  bottom right: La<sub>3</sub>Si P 4=m bm  $.^{32}$ 

isolated ad-atom  $s^{33}$  and La-dim ers in order to provide an understanding of the constituents of the more extended structures. Chain structures are more stable by 0.34-0.40 eV per La atom as compared to isolated ad-atom s.

Similar to  $Sr_{,}^{15}$  we nd the most stable position of an isolated La atom at position A, in the center of four Sidimers (compare Fig. 1). The position D, B and C have energies 0.23 eV, 0.51 eV and 1.70 eV higher than position A. A (4 4) supercell has been used for these calculations.

The di usion barrier along the valley is equal to the energy di erence between sites A and B, namely  $0.52 \ eV$ , the one across the row is  $1.31 \ eV$  and is estimated by the midpoint between the sites A and D.

The form ation of La dim ers low ers the energy per adatom by  $0.10\{0.18 \text{ eV} \mod \text{pared} \text{ to isolated ad-atom s.}$ Due to the topology of the Si(001) surface, three di erent types of La-dim ers can be form ed: (1) orthogonal to the Sidim er row s, (2) parallel to the Sidim er row s and (3) diagonal to the Sidim er row s. All three structures are shown in Fig.3. We nd that the parallel La-dim er is low est in energy, follow ed by the orthogonal and diagonal La-dim ers. All La-dim ers lie within a sm all energy window of 0.08 eV. Note, that we only investigated singlet states.

A pair of La atom s has six valence electrons and from the lessons learned from Sradsorption, one would assume that three Sidim ers in the vicinity of the Ladim er get unbuckled. This is, however, not the case. Only two Sidim ers become fully unbuckled. The remaining two

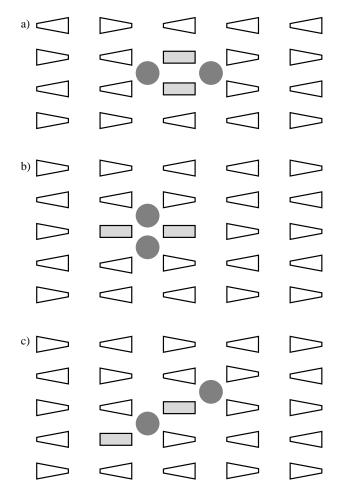


FIG.3: Schem atic representation of isolated La-dim ers on the Si(001) surface. The lled circles represent the La ad-atom s, the rectangles represent a lled and therefore unbuckled Sidim ers. The triangles represent buckled Si-dim ers. The at side of a buckled dim er indicates the upper Si atom with a lled dangling bond, whereas the pointed side indicates the low er Si atom with the empty dangling bond. Only the Sidim ers which are clearly unbuckled have been drawn as rectangles. The partially unbuckled ones are represented by triangles (see discussion in section V). The supercells used for the total energy calculations are shown in Fig. 14.

electrons from the La-dimer enter into states that are derived from the upper dangling-bond band and which have an admixture of the La-d and f states.

U sually one can easily distinguish between buckled and unbuckled dimers. In the vicinity of La-dimers oriented diagonally or orthogonally, however, we also observe Sidimers with an intermediate buckling amplitude. Thus, in these cases, the oxidation state of the La atom, namely 2+ versus 3+ cannot be attributed in a unique manner.

For the orthogonal and diagonal La-dim ers we observe a tendency for the La atom s to reduce their distance com – pared to staying centered on A sites by 1 { 4%. For the parallel La-dim er this e ect is opposite and much larger. The distance between the two La atom s is 4.11A, com pared to 3.84A between two A sites which am ounts to an expansion of 7%. This ad-atom repulsion within one valley has already been observed in case of  $\mathrm{Sr}^{15}$  and explains the form ation of isolated chains instead of condensed chains or clusters at low coverages. Nevertheless, we not the parallel diment to be the most stable.

## VI. CHAIN STRUCTURES AT LOW COVERAGES

As we combined pairs of the most favorable site for isolated La ad-atom s into dimers, we now search forways to stack the three types of La-dimers together into more extended structures.

W e system atically approached linear chain structures. Each of the three La-dim er types { parallel to the Sidim er row, orthogonal or diagonal { has been stacked such that it shares at least one Si-dim er, so that this Sidim er is next to two Lanthanum atom s from di erent Ladim ers. The energetic ordering has been deduced on the basis of binding energy per La atom (com pare Tab.III). N ote that the binding energy per La atom for a given chain structure is slightly coverage dependent. In case of the double stepped chains (com pare Fig. 4a for the structural principle) the adsorption energy varies w ithin 0.06eV at coverages between 1/10 and 1/5 M L. In order to ensure com parability all num bers listed here refer to a coverage of 1/6 M L.

We start our investigation with parallel La-dimers shown in Fig. 3b, which is the most stable dimer structure. The most favorable chain in this class is stacked perpendicular to the Sidimer rows as shown in Fig. 4c. Its energy lies 0.06 eV per La atom above the lowest energy chain structure.

The most favorable chain made from orthogonal Ladimers is shown in Fig. 4a. It can also been interpreted as a variant of a chain of diagonal La-dimers (compare Fig. 3 c). This is the most favorable chain structure of La atom s on Si(001). Its chains run at an angle of about 76 to the Si-dimer row. It should be noted that it is equally possible to arrange the La-dimers in a zig-zag manner as shown in 4b. The zig-zag chain has not been explicitly calculated. The coexistence of straight and zig-zag chains has been found for Sr on Si(001), where the two modi cations have been shown to be almost degenerate in energy.<sup>15</sup>

In all low-energy structures each La atom is thus surrounded by four silicon atoms having led dangling bonds. Three of them are partners of led Sidim ers while one is a buckled Sidim erw ith the negative Siatom pointing towards the La ad-atom. On the basis of counting unbuckled Sidim ers, these structures are in a 3+ oxidation state.

The La-chain is the con guration with lowest energy in the low coverage limit. The lowest energy chain structures are of the order of 0.17 eV per La atom more stable than the most favorable isolated La-dimer. At elevated tem peratures, entropic elects will lead to increasingly

La-dim er type	E [La] [eV ] panel			
parallel	90	-0.30	а	
parallel	63	-0.15	b	
parallel	45	-0.20	С	
parallel	34	-0.13	d	
parallel	0	-0.07	е	
orthogonal	90	-0.26	f	
orthogonal/diagonal	76	-0.36	g	
diagonal	63	-0.28	h	

TABLE III: Energies per La atom of the chain structures at  $1/6 \,\mathrm{M}$  L. The orientation of the chain is described by the angle

(degrees) of the chain to the Sidim er row. The supercells used for the total energy calculations are sketched in the corresponding panels of Fig. 15.

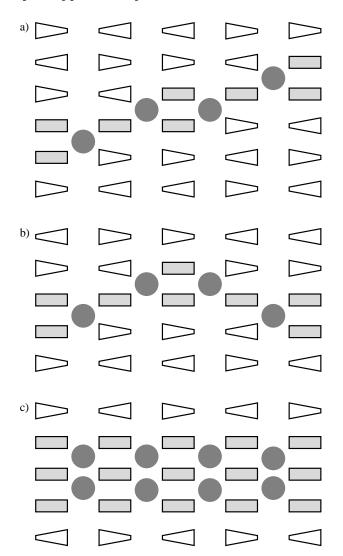


FIG. 4: Schematic representation of isolated La ad-atom chains. a) a single, double-stepped La chain. This is the energetically most favorable surface reconstruction at low coverages. A change in chain direction is realized by stacking two La-dimers with di erent orientation (b). Panel (c) shows the lowest energy chain structure derived from parallel dimers.

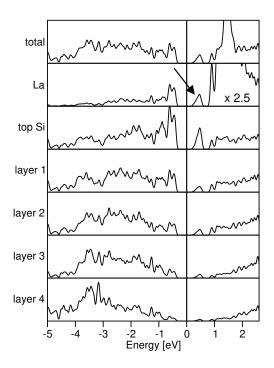


FIG.5: Layer resolved density of states of 1/5 M L.The arrow indicates the upper dangling bond bands in the gap of silicon. The La panelwasm agni ed by a factor of 2.5. The seem ingly large gap of the silicon substrate is due to nite size e ects and also found for the clean silicon surface at this slab thickness. For bulk silicon we obtain a "typical" GGA value of 0.65 eV. This DOS corresponds to the supercell outlined in Fig.6b.

shorter chain fragments. From the energy-di erence of the linear chain and the isolated La-dimer, we obtain an estimate for the chain term ination energy of approximately  $0.09 \, \text{eV}$ . It should be noted, that experiments often observe shorter chain sequences than predicted from thermal equilibrium as high-temperature structures are frozen in.

The electronic structure of the La-chain is analogous to that of the Sr single chain.<sup>15</sup> The empty silicon surface has an occupied and an un-occupied band form ed from the dangling bonds of the Si-dim ers. La donates electrons into the upper dangling bond band. Those dangling bond states, which become lled, are shifted down in energy due to the change in hybridization on the one side and due to the proximity of the positive La-cations on the other side.

## VII. CONDENSED CHAINS

W ith increasing coverage, the chains become closer packed. In the case of Sr, there was a preference for a periodicity of (2n + 1) surface lattice spacings along the Sidim er row direction.<sup>15</sup> This restriction has been attributed to the requirem ent that every cation be surrounded by four Siatom swith lled dangling bonds, and that there is no frustration of the Sidim er buckling, i.e. adjacent Sidim ers are buckled antiparallel.

For La the situation is more complex. Due to the longer periodicity of the La chains compared to those of Sr, there are two families of chain packing for La as shown in Fig. 6. In the rst family the La chains are displaced only parallel to the Si-dimer row direction. In the second family the chains are in addition displaced perpendicular to the Si-dimer row.

The rst fam ily has a preference of (2n + 1) surface lattice spacings along the dimer row as in the case of Sr adsorption. The spacing in the second fam ily is arbitrary. The reason is that in fam ily one, the buckling of every second Si-dimer row is pinned on both sides by two neighboring La chains (see Fig. 6a). A Si-dimer is pinned, if its buckling is determined by the C oulom b attraction of its raised, and thus negatively charged, Si atom to a nearby La ion. Since the buckling alternates along the Sidimer row, this pinning can lead to indirect, long-ranged interaction between di erent La-chains.

In the second family the buckling of every Sidim errow is pinned only at one La-chain as seen in Fig. 6b, while there is no preference of the Sidim er buckling at the other La-chain. Thus for Lawe nd { in contrast to  $\mathrm{Sr}^{15}$  { arbitrary chain spacings.

The closest packing of La-chains before they merge is 1/5 M L. We consider two La-chains merged if La atom s of di erent La chains occupy nearest-neighbor A sites within one valley. We predict a distinct phase at this coverage as seen in Fig. 12 and discussed later. This structure, shown in Fig. 6b, is derived from chains of the second family. An explanation for noting a phase at 1/5 M L is that the energy at higher coverage increases due to the electrostatic interaction of the La atom swithin one valley. For the rst family, the highest possible coverage before La-chains merge is 1/6 M L (Fig. 6a).

Note that the chains can change their direction without appreciable energy cost as shown in Fig. 4b. Experimentally measured direction patterns would reject a con gurational average.

The layer resolved density of states is shown in Fig.5. We see that the Ferm i-level lies in a band gap of the surface. Above the Ferm i-level and still in the band-gap of bulk Si, surface bands are form ed, which originate from the remaining empty dangling bonds of the buckled Sidim ers. As in the case of Sr, these states form at bands in the band-gap of silicon, which approximately remain at their energetic position as the La coverage is increased. Its density of states, how ever, scales with the number of empty dangling bonds.

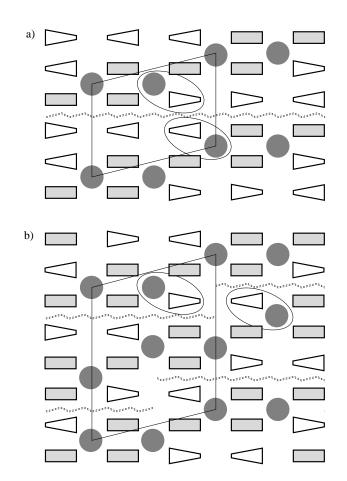


FIG. 6: Schem atic representation of the two packing types of double stepped La chains at their maximum condensed coverage. The reconstruction in panel a) consists of parallel La chains. The chains in panel b) are also displaced by one valley orthogonal to the Sidim er rows. The ovals indicate the pinning of the Sidim er buckling by a La ad-atom. The dashed double zig-zag lines shows the positions where, in case of structure a), an even number of Sidim ers can be inserted in order to arrive at m ore dilute coverages. In case of structure b) an arbitrary number of Sidim ers can be inserted, as the buckling of each row is just pinned on one side. The calculational supercells are outlined.

# V III. THE CANON ICAL SURFACE AT 1/3 M L COVERAGE

If the spacing of the chains is further reduced, they condense at 1/3 M L to the structure shown in Fig.7.

There are several versions of this structure type. They have a repeating sequence of two La-atom s and one vacant A site in each valley in common. The relative displacement of this sequence from one valley to the next, how ever, may dier. We investigated several structures and found the one shown in Fig. 7 to be the most stable.

A structure with a sequence of four A sites occupied with m etalions separated by two empty A sites, has been the m ost favorable structure at this coverage in the case of Sr adsorption.<sup>15</sup> For La, how ever, this con guration is

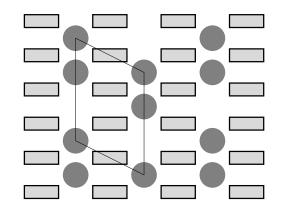


FIG. 7: Schem atic representation of the most stable reconstruction at the canonical coverage of 1/3 M L. All Sidim er dangling bonds are lled. This structure can be thought of as the condensed chain structure in Fig. 6 b) with a reduced chain spacing. The calculational supercell cell is outlined.

energetically unfavorable.

At a coverage of 1/3 M L, all silicon dangling bonds are led due to the electrons provided by the La adatom s. This surface is isoelectronic to the Sr covered surface at 1/2 M L.<sup>15</sup> For the Sr-covered silicon surface, the increased oxidation resistance of the corresponding 1/2M L structure has been observed experim entally.<sup>34</sup> Sim ilarly we suggest that the surface covered with 1/3 M L of La will have an increased oxidation resistance.

In Fig.8 we show the layer-resolved density of states of the most stable structure at 1/3 M L. In analogy to the 1/2 M L covered Sr surface, there are no surface states deep in the band gap of silicon, because all Sidim er dangling bonds are lled and shifted into the valence band due to the electrostatic attraction of the electrons to the positive La ions. Note, how ever, that in contrast to the canonical surface coverage of Sr on Si(001) at a coverage of 1/2 M L, the canonical La surface exhibits vacant A-sites.

# IX . TRANSITION FROM LA $^{3+}$ to LA $^{2+}$ Above 1/3 m L

Up to the canonical coverage of 1/3 M L, all therm odynam ically stable reconstructions could be explained by La being in the 3+ oxidation state. In contrast to the isolated La-atom s and La-dim ers, the oxidation state can clearly be identi ed from the number of unbuckled Sidim ers: E ach unbuckled dim erhas received two electrons. A 3+ oxidation state is also consistent with the density of states.

If we follow the picture that emerged from Sr, we would anticipate that increasing the coverage above 1/3 M L in case of La would lead to lling the Si-dim er antibonds, which results in a breaking up of the dim er bonds. For La the situation is di erent: the La-d band is located at much lower energies as compared to Sr. Therefore

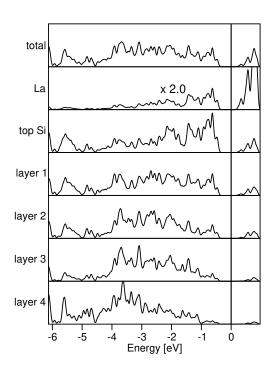


FIG. 8: Layer resolved density of states of 1/3 M L. The La panel was magnied by a factor of 2. Com pare Fig. 5 for a discussion about the Siband gap. This DOS corresponds to the supercell outlined in Fig. 7.

the energy to break the Sidim er bonds is larger than that to add electrons into the La d-shell. As a result we nd that La changes its oxidation state from 3+ to 2+. O xidation states of La that are even low er are unfavorable due to the C oulom b repulsion of electrons within the Lad and f shells. Thus the structures above  $1/3 \,\mathrm{M}$  L can be explained in term s of La<sup>2+</sup> ions and are sim ilar to those found for Sr.<sup>15</sup>

It may be instructive to compare two structures with di erent oxidation states of La. A good example is found at a coverage of 2/3 ML: The lowest energy structure is a (3 1) reconstruction already found for  $Sr^{15}$  and depicted in Fig. 9a. This is a clear 2+ structure. Since every Sidim er only accepts two electrons, they can just accomm odate two of the three valence electrons of La. The lowest structure with form al La<sup>3+</sup> ions, which can clearly be identied as having all Sidim er bonds broken, is shown in Fig. 9b. It has an energy which is 0.36eV per La atom higher than the structure with La<sup>2+</sup> ions.

At 1/2 M L, we nd a structure where all A sites are occupied to be most stable. There the La d-states are partially occupied. We con rm ed that the system is not spin polarized.

The crossover of the energy surfaces of the 2+ and the 3+ structures is shown in Fig. 10 using a set of surface reconstructions, for which the charge state can be

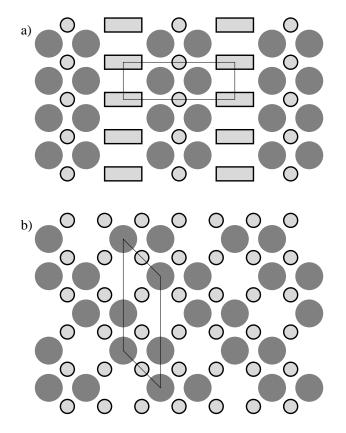


FIG.9: The lowest energy structures at 2/3 M L in the 2+ (a) and 3+ (b) regime. The calculational supercells are outlined.

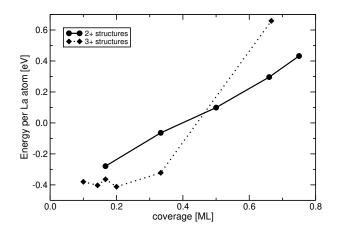


FIG.10: C rossover of the total energy surfaces of the 2+ and 3+ regim e beyond the canonical coverage of 1/3 M L.

determ ined unambiguously. It can be clearly seen that the 2+ structures become signi cantly more stable above 1/2 M L. From Fig. 11 it is apparent that the energy rises sharply as the La atom s cross over to the 2+ oxidation state beyond the canonical interface at a coverage of 1/3 M L.

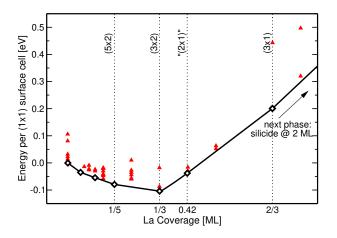


FIG.11: (C olor online) The surface energy<sup>35</sup> versus coverage. The open diam onds correspond to the therm odynam ically accessible surface structures while the triangles mark m etastable structures. C om pare Figs. 6b, 7 and 9a for the structures at 1/5, 1/3 and 2/3 M L, respectively. At 0.42 M L we predict a (2 1) reconstruction which originates from the half-M L structural tem plate with a La vacancy concentration of 17% (see discussion in the text).

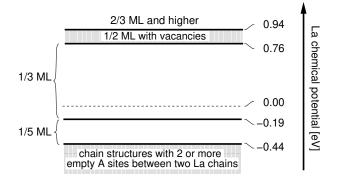


FIG.12: The phase diagram for La adsorption on Si(001).

### X. PHASE DIAGRAM

Based on the surface energies composed in Fig. 11 we extracted the zero-K elvin phase diagram shown in Fig. 12. The slope of the line-segments of the lower envelope in Fig. 11 corresponds to the chemical potential, at which the two neighboring phases coexist (for a more elaborate discussion, refer to R ef.<sup>15</sup>). The stable phases are de ned by the coverages where two line segments with di erent slopes meet. The zero for the La chemical potential has been chosen as the value at which LaSi<sub>2</sub> and silicon coexist. Consequently, all phases in regions of positive chemical potentials are in a regime where the form ation of bulk silicides is therm odynam ically favorable.

Below a chemical potential of 0:44eV we expect single chain structures as described in Sec.VI. At 1/5 M L we predict a distinct phase since this is the highest possible coverage without La ad-atom s at nearest neighbor A sites (com pare Fig. 6b). At a chem ical potential of -0.19 eV the stability region of the 1/3 M L coverage (Fig. 7) starts.

The transition from the phase at 1/3 ML to the 2 1 reconstructed surface at 1/2 ML, where all Asites are lled, can be described by a decrease of Lavacancies (com pare Fig. 7 of this manuscript and Fig. 9 ofRef.<sup>15</sup>). From this point of view, the phase at 1/3 M L can be described by an ordered array of La-vacancies in the 1/2 M L structure. There is an e ective repulsion between La-vacancies due to the repulsion between La-atom s on neighboring A-sites. W e describe the total energy by an empirical model energy of the form  $E(C_V) = E_0 + E_f$ √C +  $c_v^2$ , where  $c_v$  is the concentration of La vacancies, E<sub>0</sub> is the energy of the structure with all A-sites led (1/2 ML), E<sub>f</sub> is the form ation energy of an isolated La-vacancy, and describes the repulsion between vacancies. Coexistence between the two phases would result from a negative value of . In that case, adding an additional ad-atom to a phase requires more energy than starting a new phase with the next higher coverage. Between 1/3 and 1/2 ML, however, is positive as lling a portion of vacancies is favorable com pared to creating patches of pure 1/2 M L coverage.

W e calculated the energy of an adsorption structure with three La atom s on neighboring A sites separated by one vacancy within one valley. La triplets in di erent valleys have been arranged, so that the distance between vacancies ism axim ized in order to m inim ize the repulsive energy. B ased on the energies at 1/3 and 1/2 M L as well as at the interm ediate coverage of 3/8 M L just described, we can determ ine the three parameters E  $_0$ , E  $_f$  and to be 0.05, -0.56 and 0.26 eV, respectively.

At a certain vacancy concentration of  $c_v^0 = 17\%$  (i.e. a La-coverage of 0.42 M L) we nd a phase boundary with the next stable phase at 2/3 M L at a chem ical potential of 0.94 eV. A coording to our phase diagram, the pure surface reconstruction at 1/2 M L is never form ed. The shaded region in Fig.12 corresponds to 1/2 M L structural tem plate with variable vacancy concentration.

A sseen in the phase diagram shown in Fig.12 bulk silicide form ation becomes therm odynam ically stable within the stability region of the 1/3 ML coverage. In a growth experiment we would expect the form ation of bulk silicide grains to be delayed beyond a coverage of 1/3 ML. The nucleation of silicide grains may su erfrom the large mism atch between bulk silicide phases and silicon. This is of particular importance during the initial stages of nucleation because the strained interface region occupies most of the volume of the grain.

Thus it may be of interest to know the stability of silicide thin  $\ln s$  on Si(001). We found one such silicide layer which is shown in Fig. 13. It consists of a (1 1) silicon surface in contact with two La layers that sandwich a layer of Si<sup>4</sup> ions in between. While we have not performed a thorough search of other candidates, the energy of this silicide layer indicates that silicide form ation will at the latest be initiated beyond a coverage of 2/3 ML.

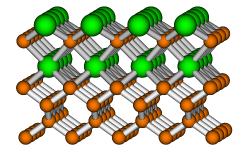


FIG.13: (Color online) Silicide overlayer at a coverage of 2 M L.

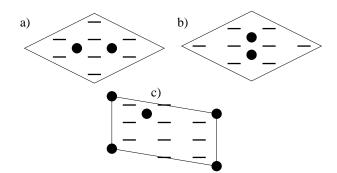


FIG.14: Supercells used for the simulation of isolated La dimers shown in Fig.3.

W e can thus only pin down the onset of silicide form ation within a coverage interval between 1/3 (therm odynam ically) and 2/3 M L (including kinetic considerations).

### XI. CONCLUSIONS

In this paper we have investigated the surface structures of La adsorbed on Si(001) as a function of coverage. W e propose a theoretical phase diagram by relating the phase boundaries at zero temperature to chem ical potentials, which can be converted into partial pressure and temperature in therm al equilibrium.

Our ndings elucidate the chem istry of third row elem ents on Si(001) and the phases of La on Si(001), and are expected to provide critical inform ation for the grow th of a wide class of high-k oxides containing La. The phase diagram m ay be used as a guide for the grow th of La-based oxides on Si(001).

# APPENDIX A:SUPERCELLS AT DILUTE COVERAGES

Fig. 3 shows the three possible La-dimerorientations on the Si(001) surface. We did not draw the periodic

in ages introduced by the calculational supercell in order to emphasize that fact that this local arrangement corresponds to an isolated dimer. Fig. 14 sketches the

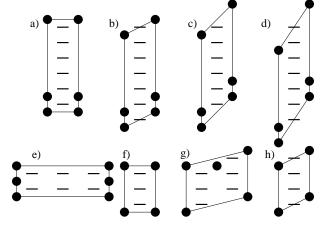


FIG.15: Supercells used for the calculation of La chains at 1/6 ML as listed in Tab.III.

supercells used. They were chosen in order to avoid frustration of Sidim ers due to periodic in ages.

Tab. III sum m arizes the energetics of chains structures built from La dimers. The supercells used in the corresponding total energy calculations are sketched in Fig. 15.

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- <sup>35</sup> The adsorption energy per (1 1) unit cell is de ned as  $E = \frac{1}{1} E$  [supercell]  $nE_0$  [m layer-Si-slab]  $E_0$  [La] X, where E [supercell] is the total energy of the supercell used for the speci c surface reconstruction, n is the number of (1 1) surface unit cells contained in that supercelland m is the slab-thickness in units of silicon layers of the supercell. I denotes the number of La atom s in the supercell and X the La coverage for that reconstruction. This energy can be alternatively calculated using the energy per La atom multiplied with the coverage X. The reference energies  $E_0$  are listed in Tab. I.